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	Examiner John T. Kwon		Art Unit 3747	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,835,878 A	11-1998	Saito et al.	701/94
	B	US-6,491,019 B1	12-2002	Apel, Peter	123/337
	C	US-6,407,543 B1	06-2002	Hagio et al.	324/207.25
	D	US-6,483,296 B1	11-2002	Hamaoka et al.	324/207.25
	E	US-			
	F	US-			
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	Examiner John T. Kwon	Art Unit 3754	Page 1 of 1

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	A	US-5,823,165	10-1998	Sato et al.	123/361
	B	US-6,067,961	05-2000	Kato, Hideki	123/399
	C	US-6,092,506	07-2000	Takagi et al.	123/399
	D	US-6,240,899	06-2001	Yamada et al.	123/396
	E	US-6,318,338	11-2001	Kawamura et al.	123/399
	F	US-6,332,451	12-2001	Sato et al.	123/399
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	H	US-6,390,062	05-2002	Saito et al.	123/361
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FORM PTO-1449

U.S. Department of Commerce
Patent & Trademark OfficeAttorney Docket No.
381AS/49700Serial No.
09/794,209

Applicant: Eisuke WAYAMA, et al.

Filing Date
February 28, 2001

Group

INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
	AA	5672818	09/1997	Schaefer, et al.			
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<i>J</i>	AL	1024267	08/2000	Europe				
	AM	1028239	08/2000	Europe				
<i>OK</i>	AN	19903490	08/2000	Germany				
	AO	19547408	07/1997	Germany				
	AP							

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John Kwon
Primary Examiner

DATE CONSIDERED

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U.S. Department of Commerce
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Attorney Docket No.
381AS/49700

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U.S. PATENT DOCUMENTS

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<i>[Signature]</i>	AA	4392375	07/1983	Eguchi, et al.			
<i>[Signature]</i>	AB	5528139	06/1996	Oudet, et al.			
<i>[Signature]</i>	AC	6448762	09/2002	Kono, et al.			
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		Applicants EISUKE WAYAMA ET AL.	
		Filing Date FEBRUARY 28, 2001	Group Art Unit:

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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
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FOREIGN PATENT DOCUMENTS							
		Document	Date	Country	Class	Sub-class	Translation Yes No
	AF	JP 9-32588	2-04-97	Japan	1	1	abstract
	AG	JP 2845884	10-30-98	Japan	1	1	abstract
	AH						
	AI						
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EXAMINER <div style="text-align: center; margin-top: 10px;"> John Kwon Primary Examiner </div>	DATE CONSIDERED <div style="text-align: center; margin-top: 10px;"> 9/27/02 </div>
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